









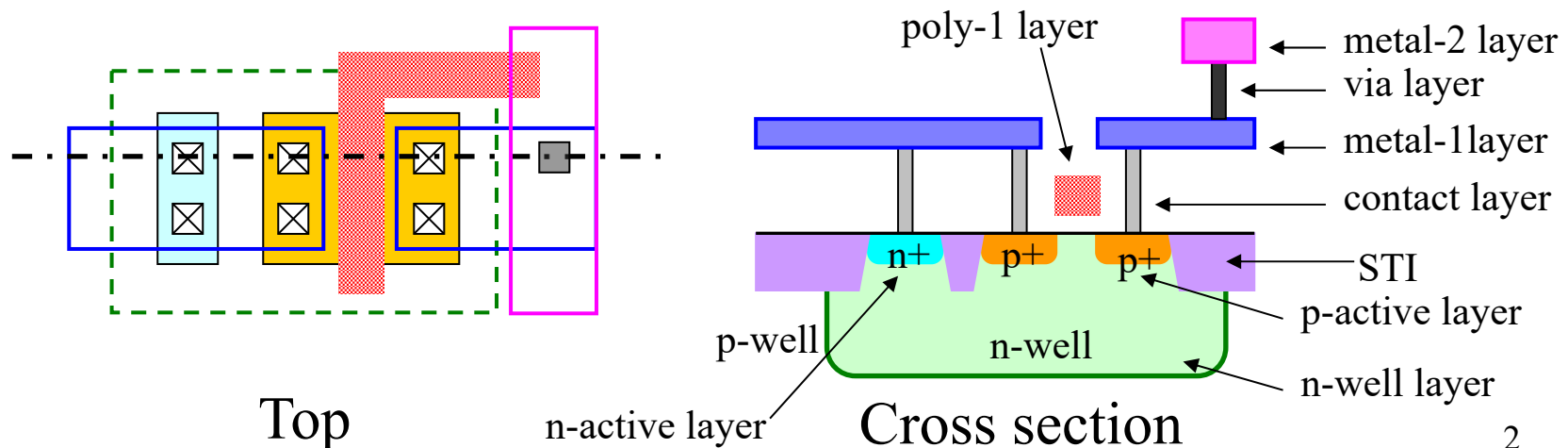
## 5.2 Layout design

Design flow of full custom LSI

# Layers

- The parts of the structure of the cross section, e.g. Metal, n-active, p-active, Poly silicon, correspond to the layers of the layout.
- The layout pattern is edited by a **layout editor**, which is a CAD software to draw the shapes on each layer and overlay them.

List of layers	
	n-well
	n-active (n+)
	p-active (p+)
	poly-1
	contact
	metal-1
	via-1
	metal-2



# Design rules

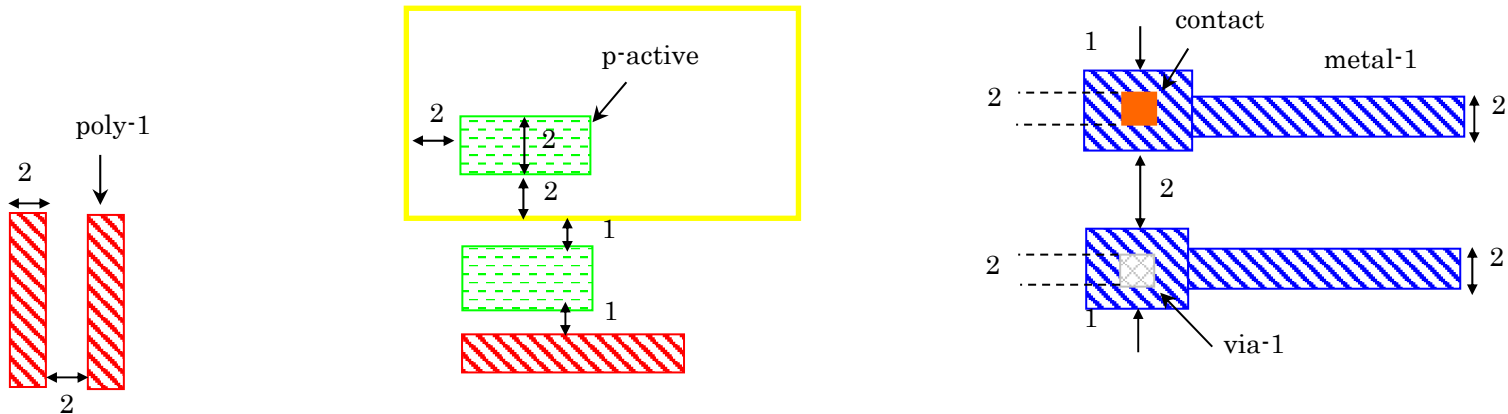
- The designers **cannot specify the dimensions of the height in cross-section structure** but design the layered structure by drawing the layout pattern.
- All layout patterns must comply with the **design rules** which is specified by the manufacture.
  - Accuracy assurance for photomask pattern
  - Accuracy assurance for microfabrication
  - Accuracy assurance for the variance of electrical characteristics
  - Preventing malfunctions due to the parasitic devices, e.g. parasitic pnp and npn (\*).

\* The adjacent pn junctions operates as a bipolar junction transistor. Unintentional short between VDD and GND may occurs (latch-up phenomenon).

# Layout verification

- Violation of design rules can be automatically detected by **DRC (Design Rule Check)** software.
  - A design data that violate a design rule is **not accepted by manufacture**.
- Scalable rule (Lambda rule) and micron rules
  - In the  $\lambda$  rules, all rules are defined as a function of a parameter  $\lambda$ . The feature size of the process sets to be  $2\lambda$ . The portability between technologies is enhanced by lambda rules.
  - In the  $\mu$  rules, all rules are defined in absolute dimensions. The  $\mu$  rule is adopted in advanced process technologies.
- Verifications of layout design
  - **DRC (Design Rule Check)** Design rule violation
  - **ERC (Electrical Rule Check)** Detection of open and short error
  - **LVS (Layout VS Schematic)** Equivalence between layout and schematic

# Example of design rules



## poly-1 rules

Width  $> 2$

Spacing  $> 2$

## active rules

Width  $> 2$

Spacing from well edge  $> 2$   
(Inside the well)

Spacing from well edge  $> 1$   
(Outside the well)

Spacing from poly-1  $> 1$

## metal-1 rules

Width  $> 2$

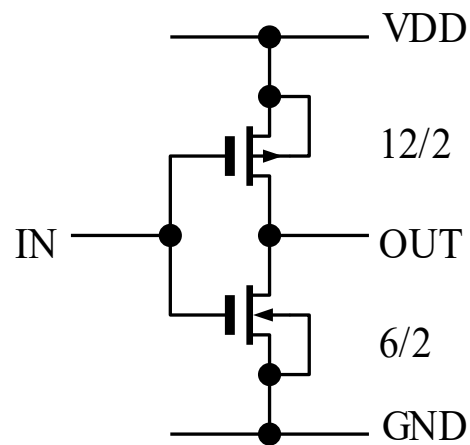
Spacing  $> 2$

Overlap with contact  $> 1$

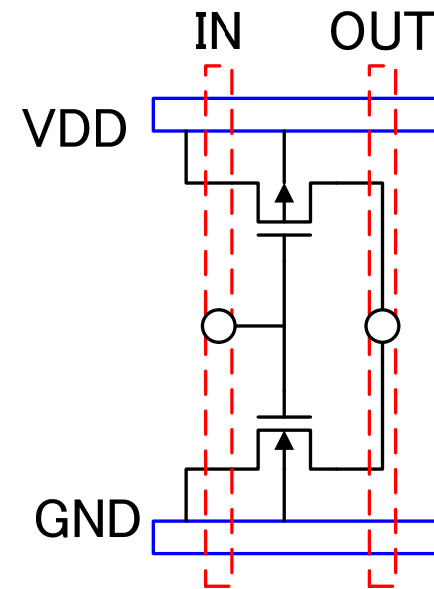
Overlap with via-1  $> 1$

# Layout design flow of inverter 1

1. Place the MOSFETs so that the wires are wire orthogonal to each other.



Schematic



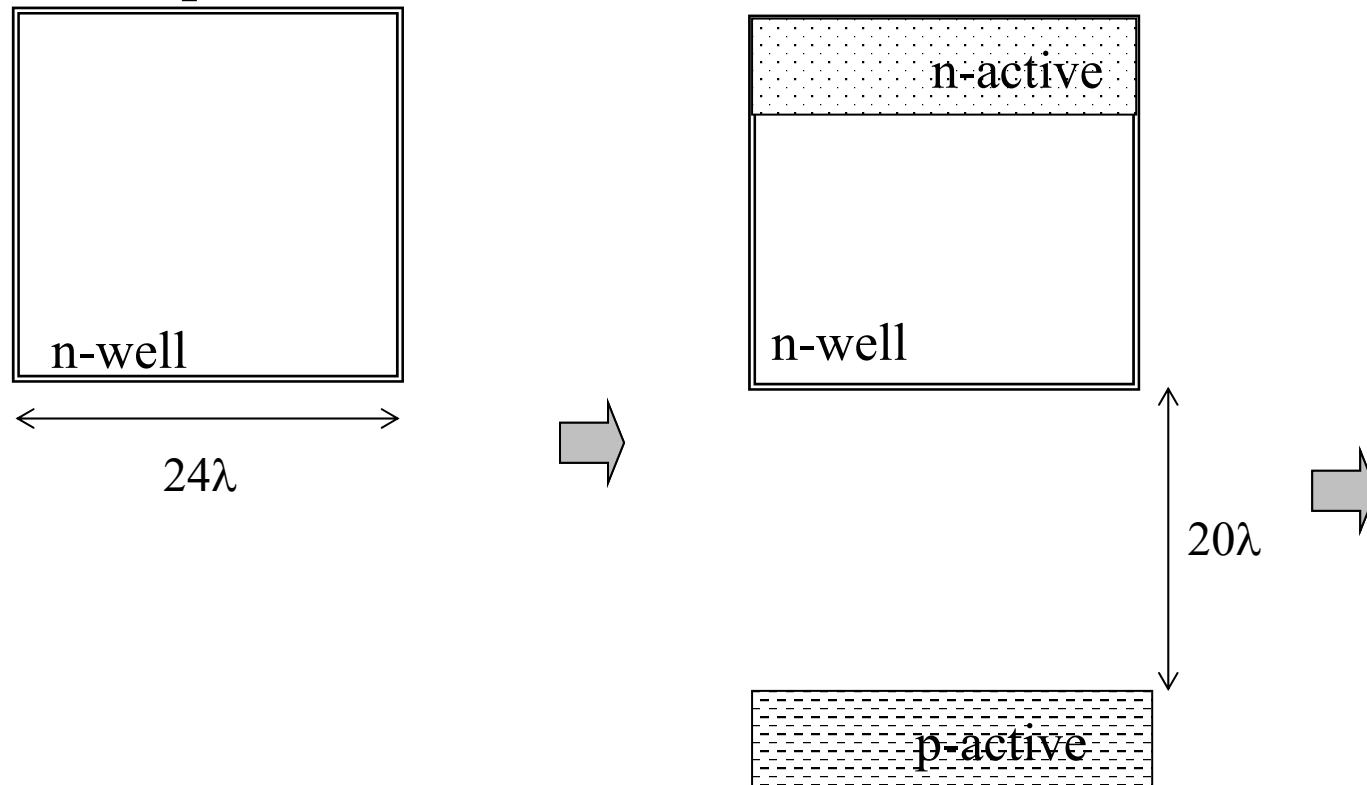
Stick diagram

(modified to design a layout)

The numbers attached to the MOSFETs (e.g. 12/2, 6/2) show the values of W/L.

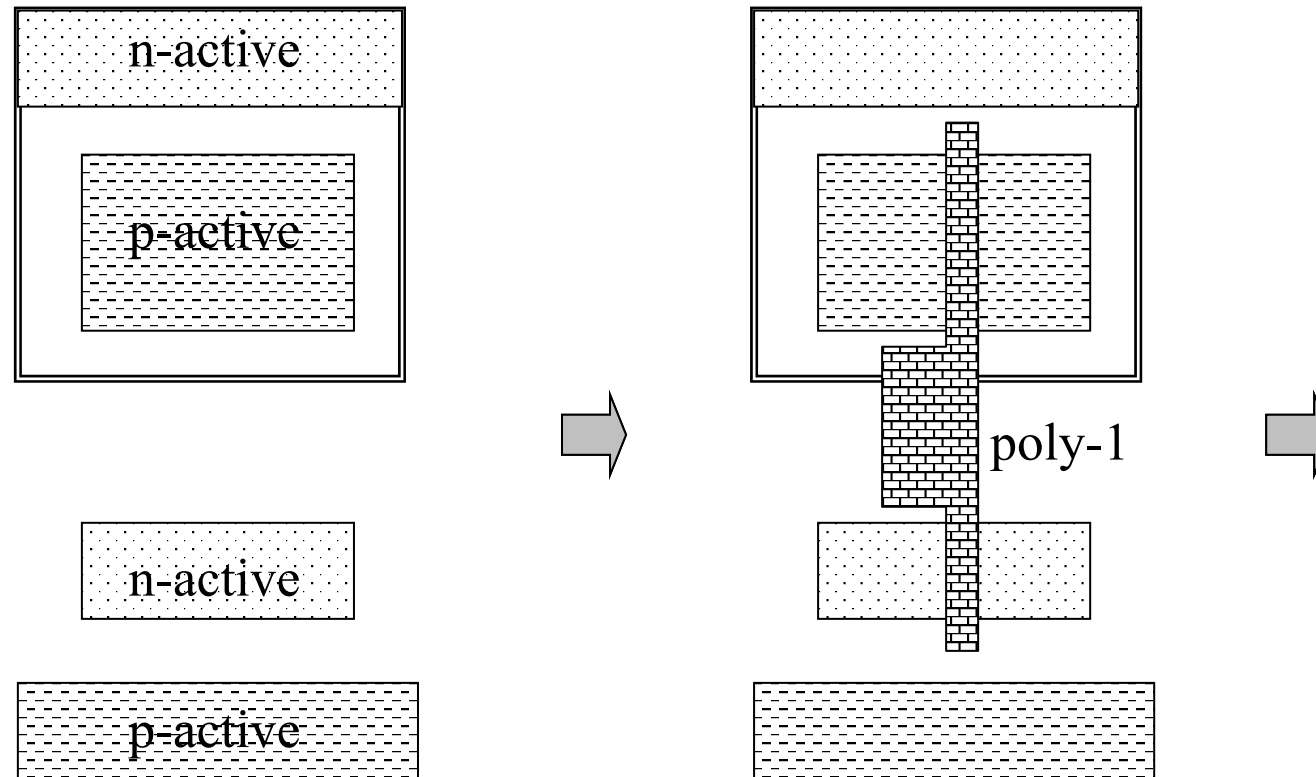
# Layout design flow of inverter 2

2. Put the n-well area.
3. Put the n-active area for the n-well contact and the p-active area for the p-substrate contact.



# Layout design flow of inverter 3

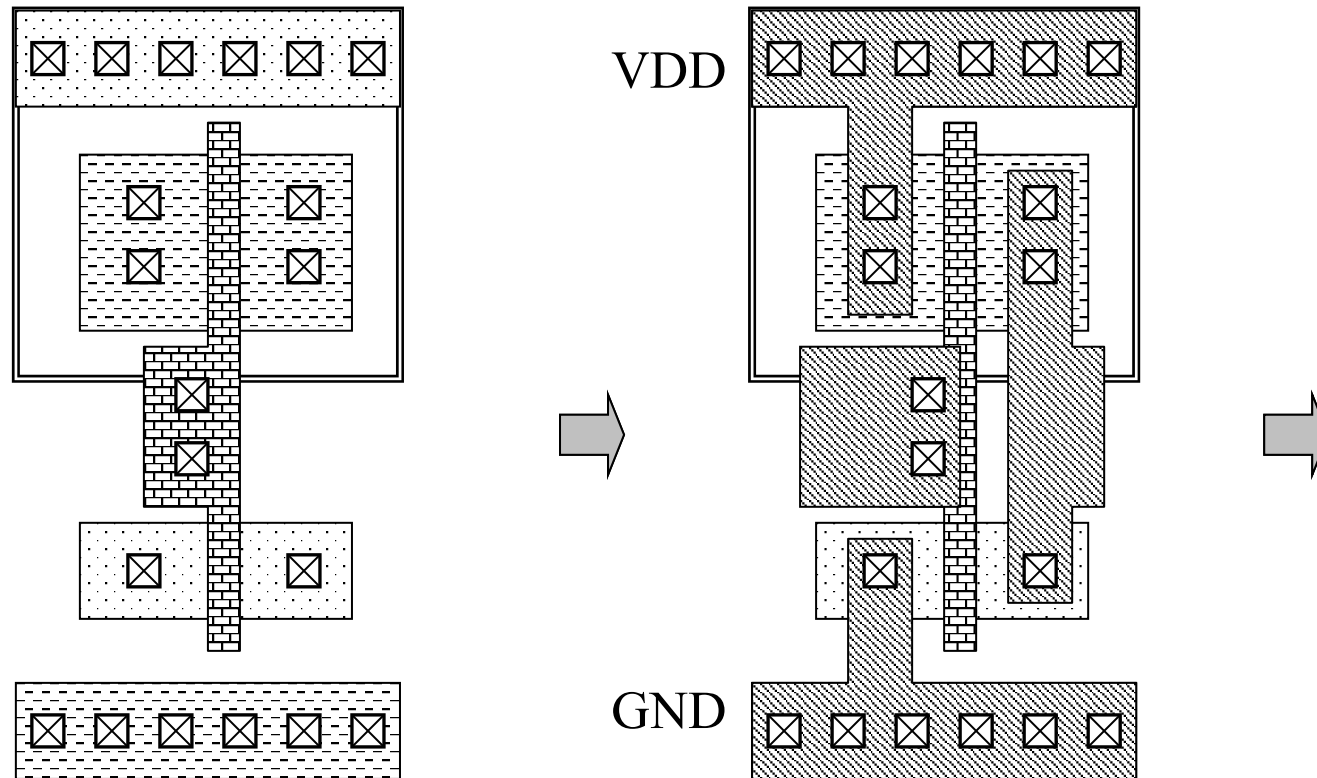
4. Draw the n-active area and the p-active area to define the source and drain of MOSFETs.
5. Put the poly-1 (Gate) electrode to separate the source and drain.





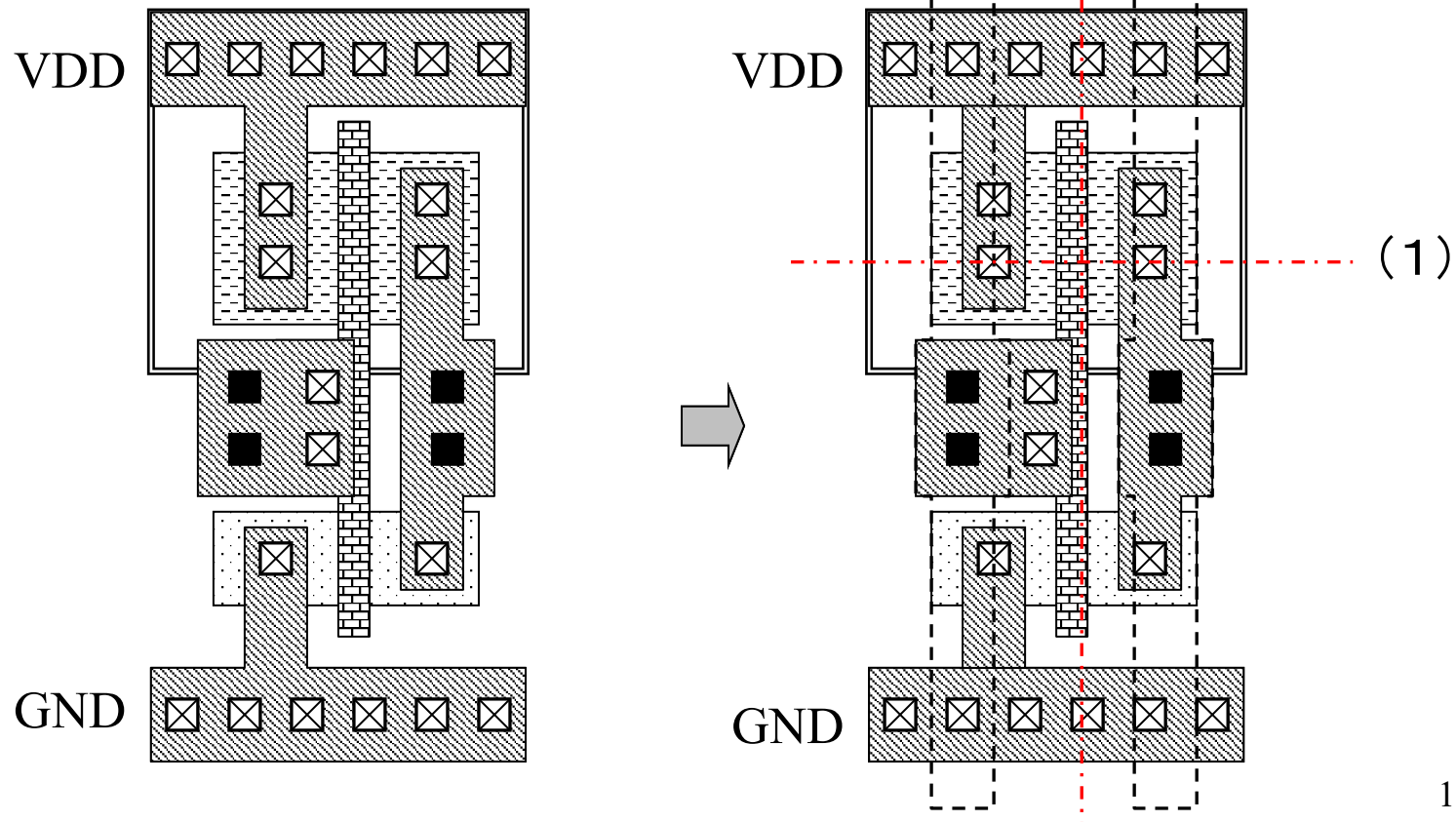
# Layout design flow of inverter 4

6. Put the contacts on the p-type and n-type active areas.
7. Wire with the metal-1.

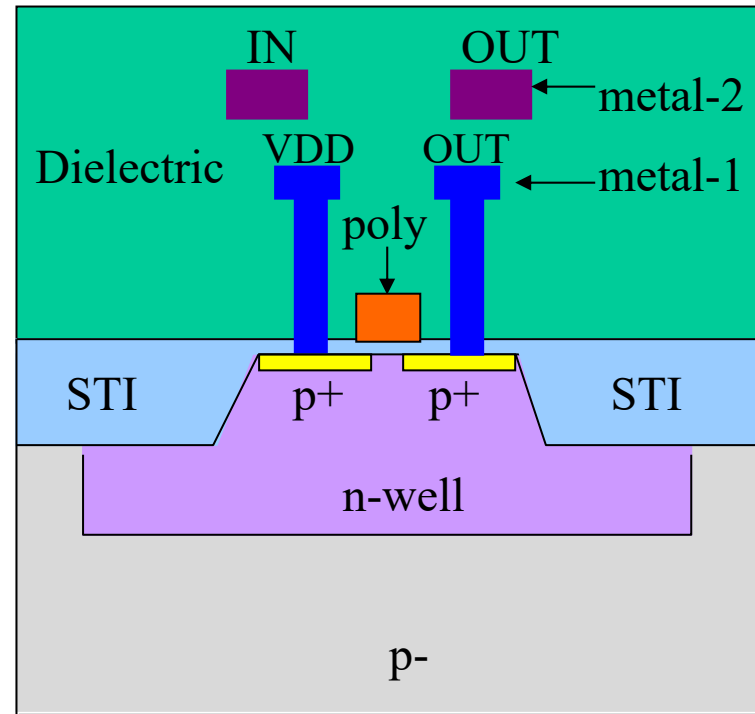
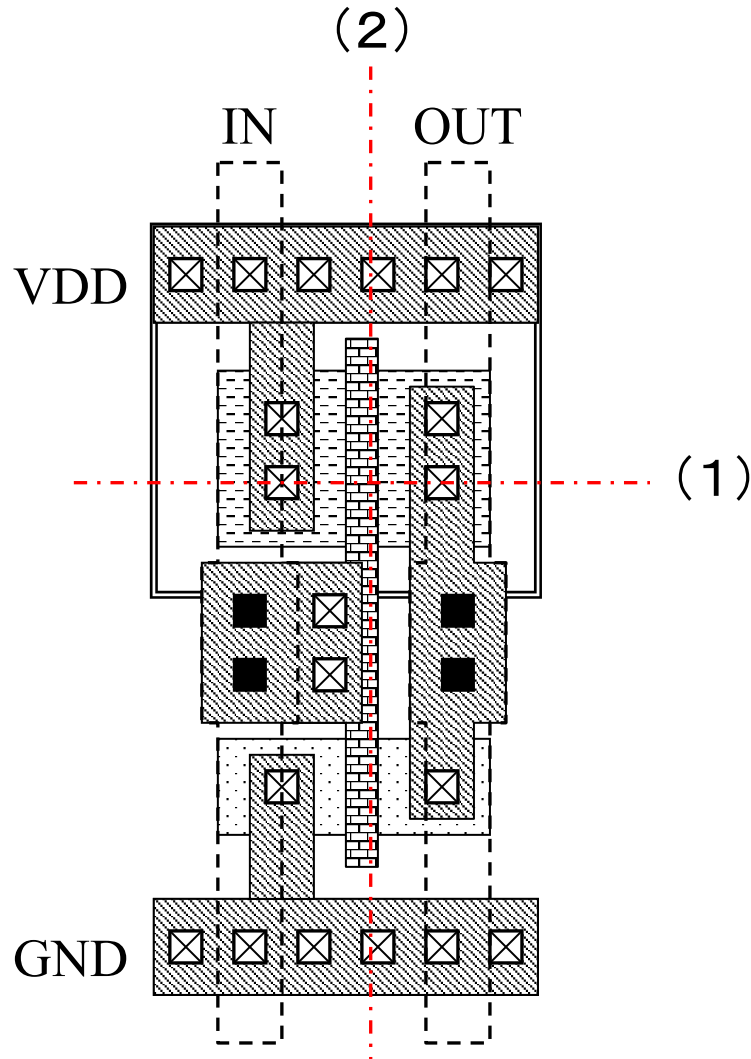


# Layout design flow of inverter 5

8. Place the via-1 on the metal-1.
9. Wire with the metal-2. (Completed)

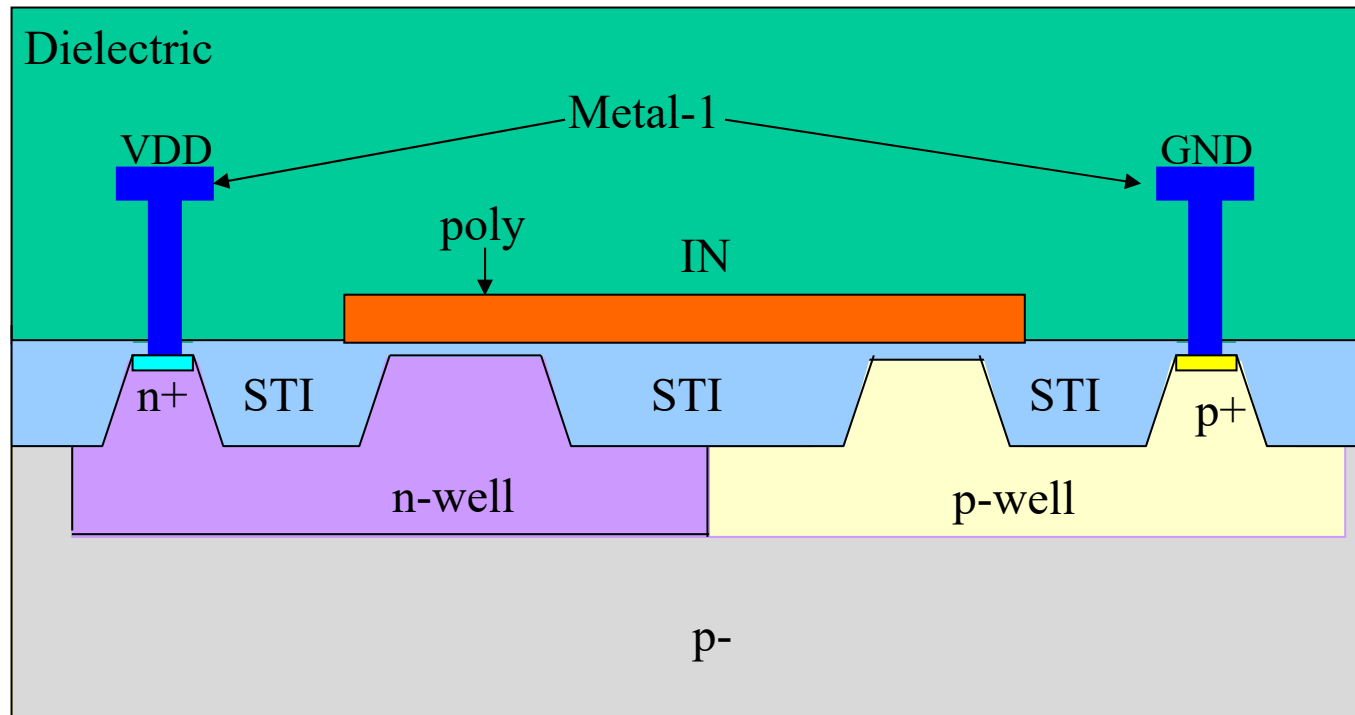


# Cross section of inverter 1



Cross sectional view along Line (1)

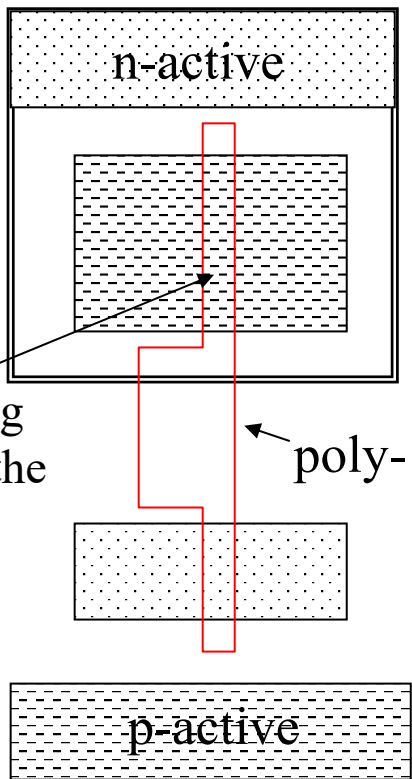
# Cross section of inverter 2



Cross sectional view along Line (2)

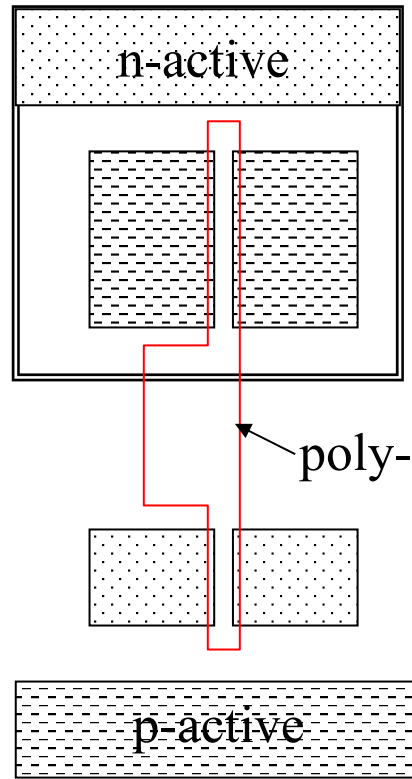
# [Important note] layout of MOSFET

○



Correct

×



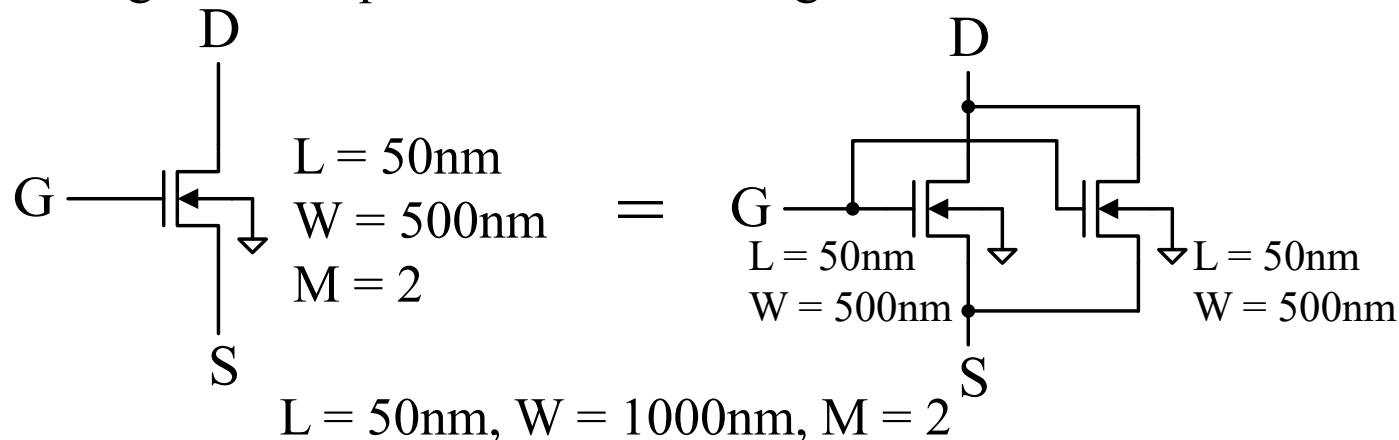
Incorrect

An overlapping area between the poly-1 and the active forms a MOSFET

If you draw the source and drain as two closed regions, the MOSFET is not formed but the gate electrode is formed on the FOX.

# Fingers of MOSFET

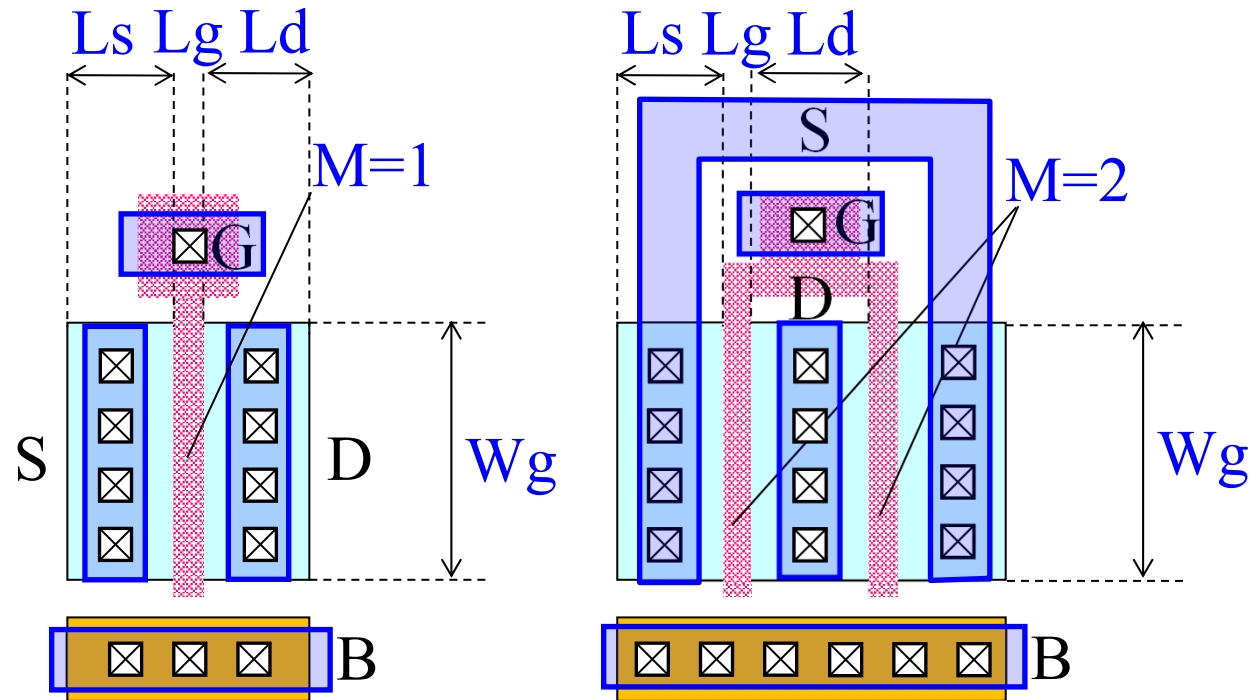
- $W/L \leq 20$  (Typically,  $W/L = 2 \sim 10$ )
  - The circuit performance is degraded with increasing  $W$  of MOSFET, because the large  $W$  causes the large parasitic resistance in the gate electrode. The value of  $W/L$  should be set within the range of 20.
- $W/L > 20$ , The parameter **M (Multiplier)** equivalently increase the value of  $W/L$ .
  - M-parameter is defined as **number of parallel connections**.
  - The large  $W$  is required to flow the large current.



# [Note] Design parameters of MOSFET

n-active (n+)    
  p-active (p+)    
  poly-Si    
  contact

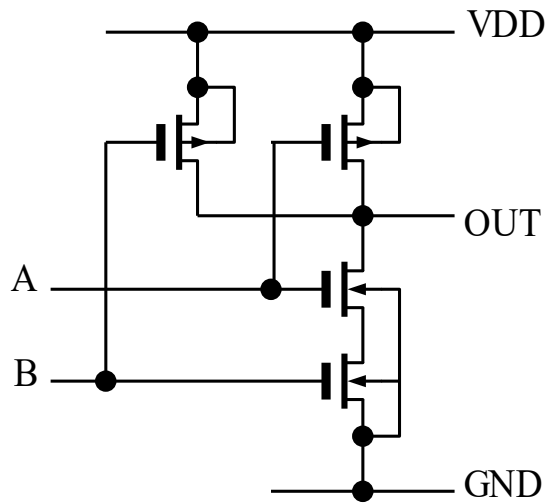
SPICE Parameter	Value
L	$L_g$
W	$W_g$
AD	$W_g \cdot L_d$
AS	$W_g \cdot L_s$
PD	$W_g + 2L_d$
PS	$W_g + 2L_s$
M	並列接続数




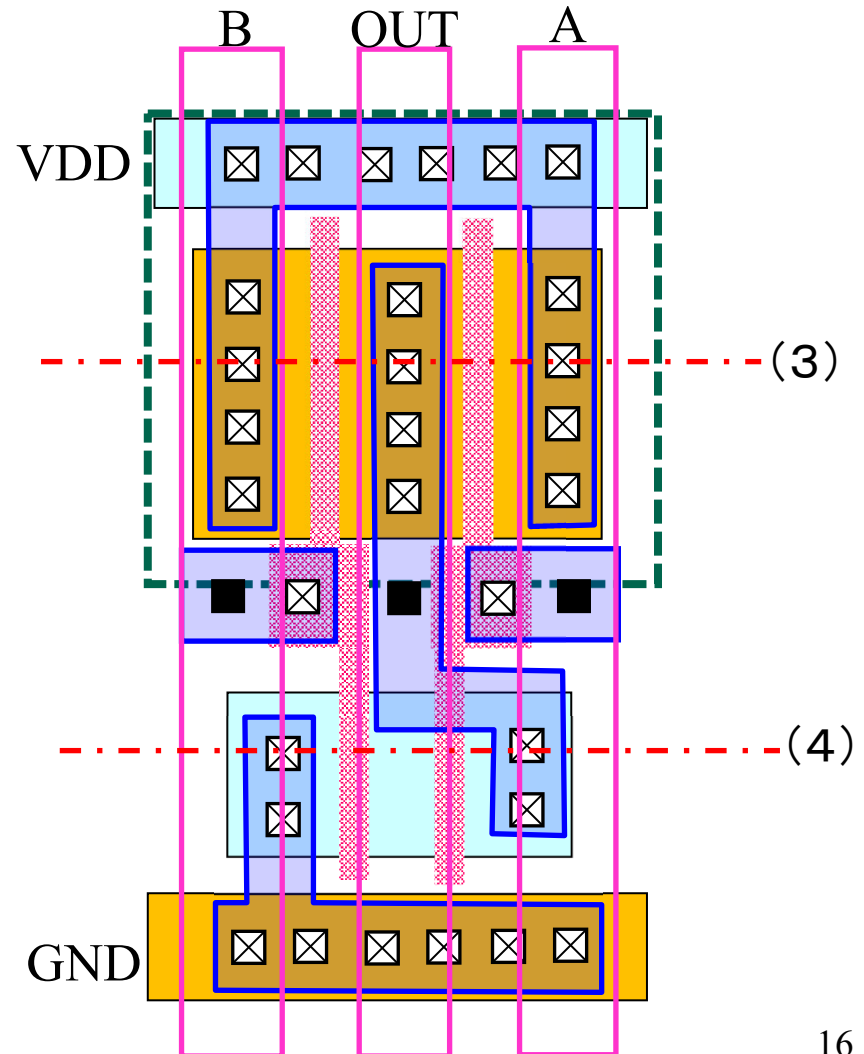
For example of  $M=2$ ,  
 $AD = W_g \cdot L_d / 2$   
 $PD = W_g + L_d$

n-ch MOSFET (M=1)     n-ch MOSFET (M=2)

# Layout of NAND

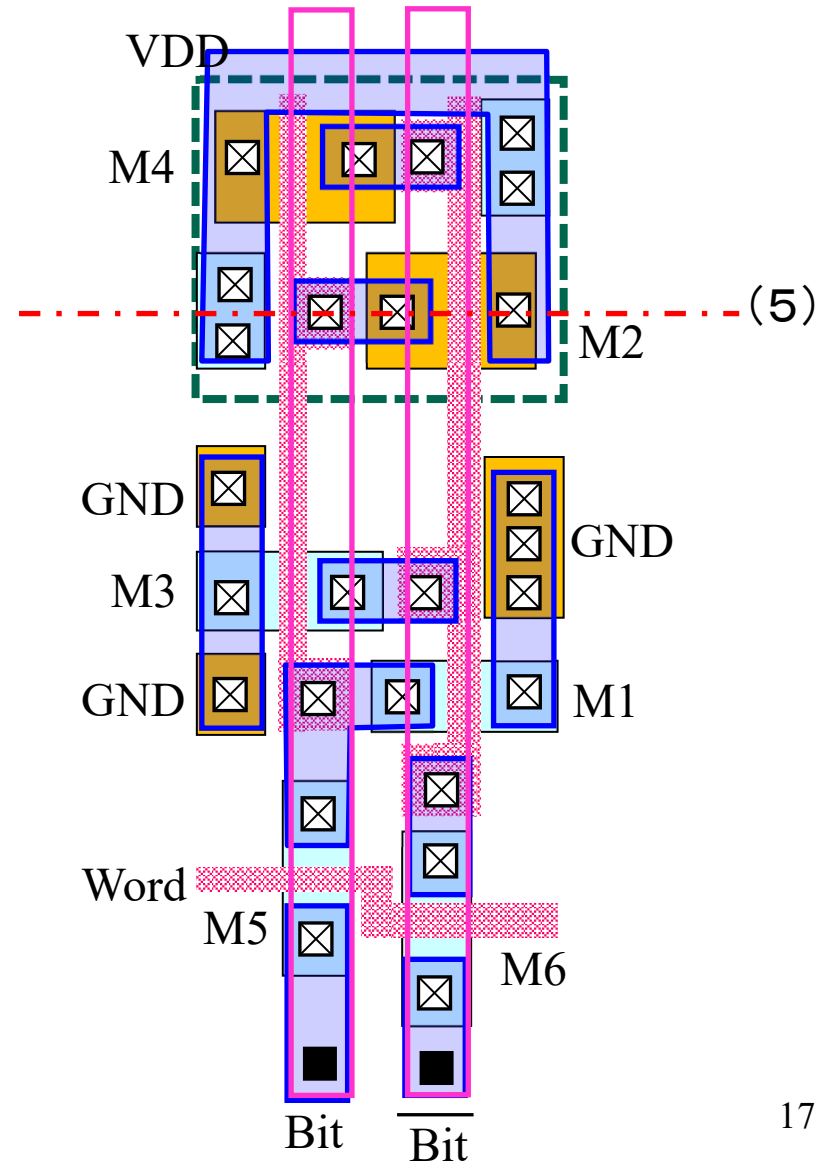
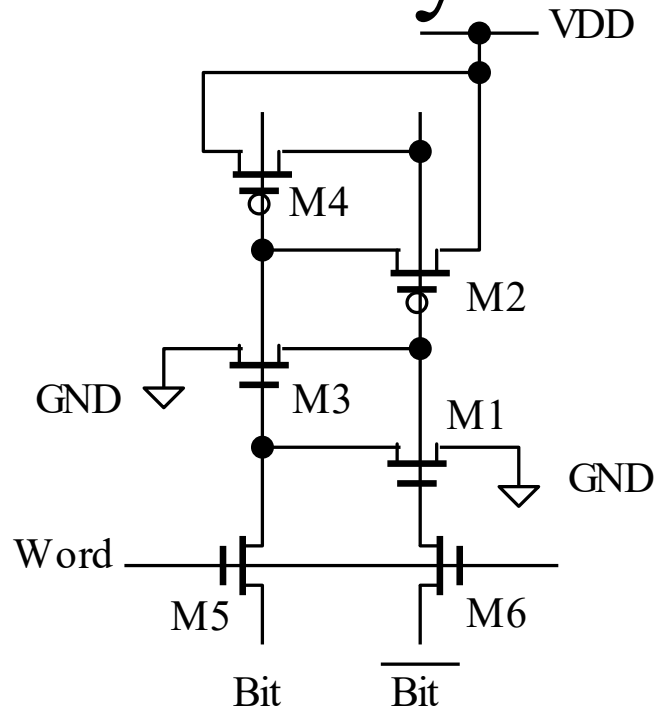



- |   |   |
|---|---|
|  n-well        |  contact |
|  n-active (n+) |  metal-1 |
|  p-active (p+) |  via     |
|  poly-Si       |  metal-2 |





# Layout of SRAM cell



- |   |   |
|---|---|
|  n-well        |  contact |
|  n-active (n+) |  metal-1 |
|  p-active (p+) |  via     |
|  poly-Si       |  metal-2 |

# Layout of memory cell array

